



temp.wsp:1

- ☐ Drafts
- ☐ Pending
- ☒ Active
 - ☒ L1: (761720) delay or delayed or delayed or d
 - ☒ L2: (37627) sense adj2 amplifier
 - ☒ L3: (2495) 1 with 2
 - ☒ L4: (1822) 1 near8 2
 - ☒ L5: (7762) bitline or bitlines
 - ☒ L6: (68570) bit adj (lines or line)
 - ☒ L7: (401) 4 with (5 or 6)
 - ☒ L8: (1814628) switches or switch
 - ☒ L9: (17140) transfer adj (gate or gates)
 - ☒ L10: (7) 7 with 9
 - ☒ L11: (11) 7 same 9
- ☐ Failed
- ☐ Saved
- ☐ Favorites
- ☐ Tagged (0)
- ☐ UDC
- ☐ Queue
- ☐ Trash

 US-PGPUB; USPAT; EPO; JPO; DI ☐ Plurals

Default operator: OR

☒ Highlight all hit terms initially

7 same 9

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20020176302	20021128	17	Cell data protection circuit	365/222	
2	<input type="checkbox"/>	<input type="checkbox"/>	US 6542426 B2	20030401	16	Cell data protection circuit	365/222	365/194
3	<input type="checkbox"/>	<input type="checkbox"/>	US 6510098 B1	20030121	12	Method and apparatus for tra	365/230.05	365/189
4	<input type="checkbox"/>	<input type="checkbox"/>	US 6335885 B1	20020101	27	Semiconductor device having	365/194	365/196
5	<input type="checkbox"/>	<input type="checkbox"/>	US 6185256 B1	20010206	89	Signal transmission system u	375/257	326/20;
6	<input type="checkbox"/>	<input type="checkbox"/>	US 5905279 A	19990518	21	Low resistant trench fill fo	257/301	257/302
7	<input type="checkbox"/>	<input type="checkbox"/>	US 4803663 A	19890207	16	Semiconductor memory having	365/189.11	365/194
8	<input type="checkbox"/>	<input type="checkbox"/>	US 4792927 A	19881220	17	Semiconductor memory device	365/189.07	365/149